

ADMENDMENTS TO THE SPECIFICATION

Please replace the title of the invention with the following rewritten title
TESTING AND INSPECTING LIGHTING INSPECTION METHOD OF A PLASMA
DISPLAY PANEL

Please replace the paragraph beginning on page 8 line 7, with the following rewritten paragraph:

Next will be described how the light inspection device performs light inspection on PDP 16. The driving waveforms to be applied to each electrode of PDP 16 in the ~~inspection~~, inspection are the same as those shown in Fig. 4. Fig. 6 shows the address pattern assigned to the sub-fields when PDP 16 undergoes the light inspection. The address pattern shows ~~that~~ which cell undergoes the address pulse voltage for producing address discharge in each address period of the sub-fields. According to the patterns shown in Fig. 6, in the first sub-field (1SF) through third sub-field (3SF), both the R-cells and the B-cells located in the rows having odd numbers continuously undergo address pulse voltage, and in 4SF through 8SF, these cells have no application of the voltage. The G-cells located in the odd-rows undergo the application of the voltage only in 4SF; in the rest of the sub-fields i.e., 1SF – 3SF, and 5SF – 8SF, the G-cells have no application of voltage. On the other hand, all of the cells located in the even-rows have no address pulse voltage during one field.

Please replace the paragraph beginning on page 13 line 24, with the following rewritten paragraph:

The presence or absence of cells that failed to light on can also be tested by an image recognition system employing a CCD camera. In this case, the inspection period is determined to be one field for each address pattern including the patterns in which the even-rows and the odd-rows are exchanged, and in which the R-cells, G-cells, and B-cells are exchanged. In the methods of the first through third embodiments, employing the aforementioned system can contribute to shortened inspection time. The presence or the absence of defective cells may be

checked by visual inspection. In this case, performing the visual inspection in a manner to continue each pattern for several fields may be a great help in judging proper operation ~~to a check person in obtaining proper judge.~~